PH3430AL

N-channel TrenchMOS logic level FET

Rev. 05 — 14 January 2010

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing and consumer applications.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- Consumer applications
- Desktop Voltage Regulator Module (VRM)
- Notebook Voltage Regulator Module (VRM)

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	30	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u>	-	-	100	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	74	W
Dynamic characteristics							
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$		-	5	-	nC
$Q_{G(tot)}$	total gate charge	$V_{DS} = 12 \text{ V}$; see Figure 14 and 15		-	19	-	nC
Static characteristics							
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 ^{\circ}\text{C}$		-	2.43	3.5	mΩ

^[1] Continuous current is limited by package.



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		
4	G	gate	[q]	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
PH3430AL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669			

4. Limiting values

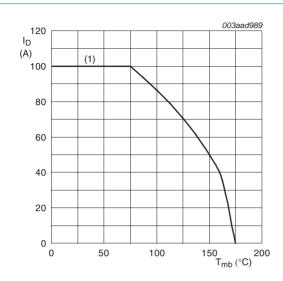
Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$		-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
V_{GS}	gate-source voltage			-20	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	<u>[1]</u>	-	86.5	Α
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	100	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see <u>Figure 3</u>		-	447	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	74	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dra	ain diode					
I _S	source current	$T_{mb} = 25 ^{\circ}C;$	[1]	-	100	Α
I _{SM}	peak source current	t _p ≤ 10 μs; pulsed; T _{mb} = 25 °C		-	447	Α
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; V_{sup} ≤ 30 V; R_{GS} = 50 Ω; unclamped		-	54	mJ

^[1] Continuous current is limited by package.

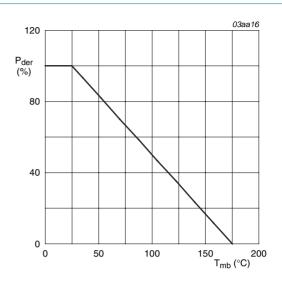
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 $V_{GS} \ge 10$ V; (1) Capped at 100 A due to package

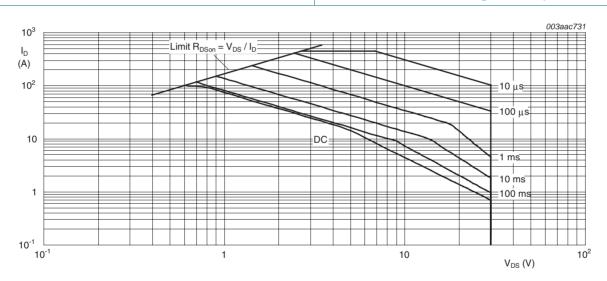
Fig 1. Continuous drain current as a function of

mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse (1) Capped at 100 A due to package.

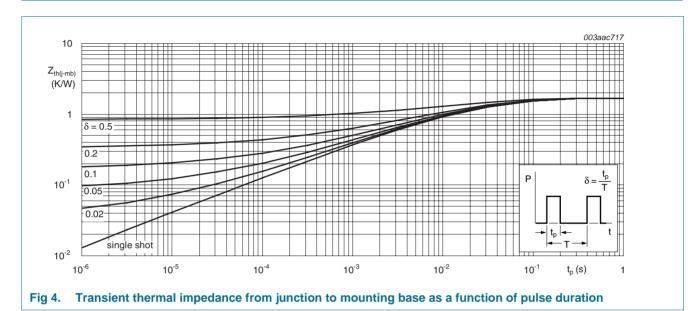
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.62	1.68	K/W



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6. Characteristics

Table 6. Characteristics

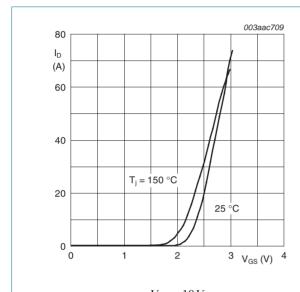
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 20 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}; t_{av} = 100 \text{ ns}$	35	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	30	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 ^{\circ}C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 11</u> and <u>12</u>	1.3	1.7	2.15	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 150 °C; see <u>Figure 12</u>	0.65	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = -55 °C; see <u>Figure 12</u>	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
		V_{GS} = -16 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nΑ
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	3.37	4.61	mΩ
resistance	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see <u>Figure 13</u>	-	-	6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	2.43	3.5	mΩ
R_G	gate resistance	f = 1 MHz	-	0.53	1.5	Ω
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see <u>Figure 14</u> and <u>15</u>	-	19	-	nC
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V$	-	37	-	nC
		$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 14</u> and <u>15</u>	-	41	-	nC
Q_{GS}	gate-source charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	6	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see <u>Figure 14</u> and <u>15</u>	-	4	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	2	-	nC
Q _{GD}	gate-drain charge		-	5	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$V_{DS} = 12 \text{ V}$; see <u>Figure 14</u> and <u>15</u>	-	2.4	-	V
C _{iss}	input capacitance	V _{DS} = 12 V; V _{GS} = 0 V; f = 1 MHz;	-	2458	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	532	-	pF
C _{rss}	reverse transfer capacitance		-	252	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	33	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	50	-	ns
t _{d(off)}	turn-off delay time		-	45	-	ns
t _f	fall time		-	18	-	ns

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Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
Source-di	rain diode						
V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 17</u>	-	0.82	1.2	V	
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	37	-	ns	
Q _r	recovered charge	V _{DS} = 20 V	-	31	-	nC	

[1] Tested to JEDEC standards where applicable.



 $V_{DS} = 10\,V$

Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values

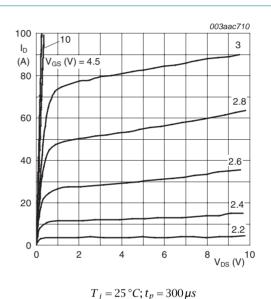
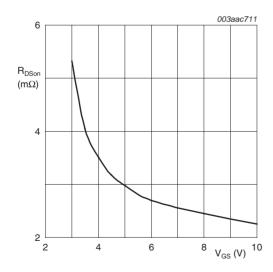
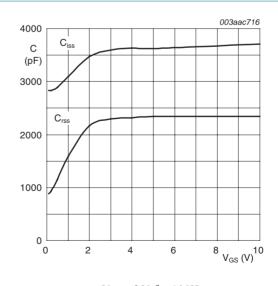


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j = 25 \,^{\circ}C; I_D = 15A$

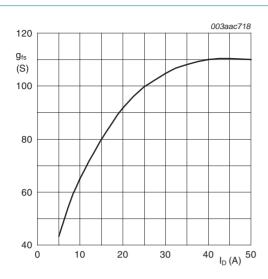
Fig 7. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $V_{DS} = 0V; f = 1MHz$

Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

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 $T_j = 25 \,{}^{\circ}C; V_{DS} = 15 \, V$

Fig 9. Forward transconductance as a function of drain current; typical values

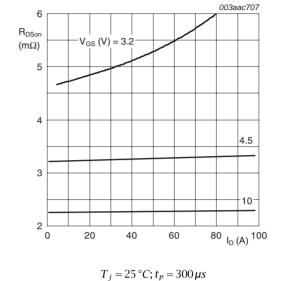
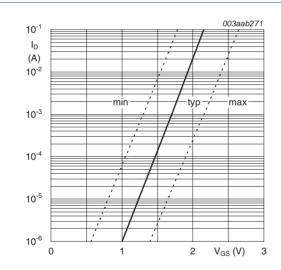
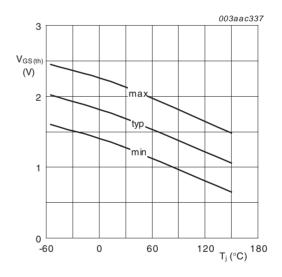


Fig 10. Drain-source on-state resistance as a function of drain current; typical values



 $T_i = 25 \,^{\circ}C; V_{DS} = 5 \, V$

Fig 11. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 12. Gate-source threshold voltage as a function of junction temperature

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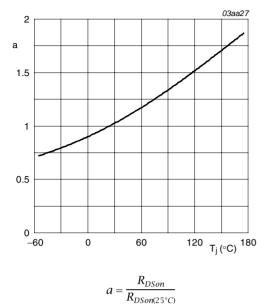


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

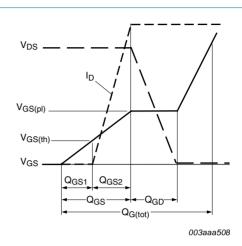


Fig 14. Gate charge waveform definitions

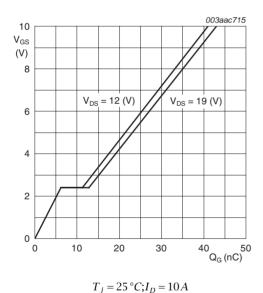
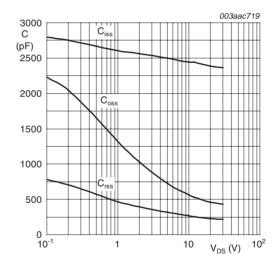


Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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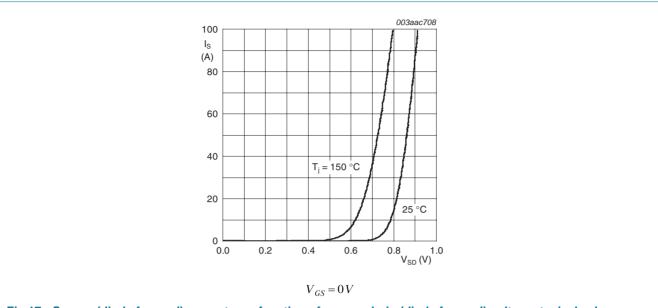
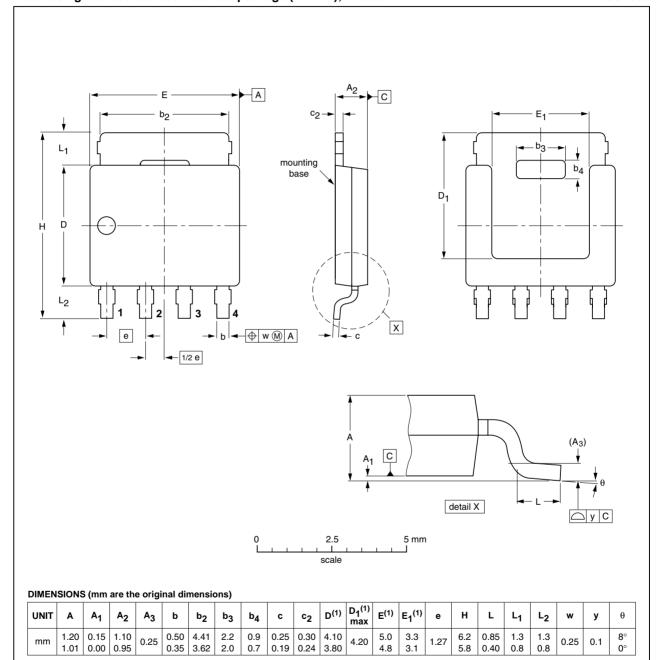


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT669		MO-235			04-10-13 06-03-16

Fig 18. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

Document ID Release date Data sheet status Change notice Supersedes PH3430AL_5 20100114 Product data sheet - PH3430AL_4 Modifications: • Various changes to content. PH3430AL_4 20091204 Product data sheet - PH3430AL_3 PH3430AL_3 20091203 Product data sheet - PH3430AL_2 PH3430AL_2 20091126 Product data sheet - PH3430AL_1 PH3430AL_1 20090121 Product data sheet - -		•			
Modifications: ● Various changes to content. PH3430AL_4 20091204 Product data sheet - PH3430AL_3 PH3430AL_3 20091203 Product data sheet - PH3430AL_2 PH3430AL_2 20091126 Product data sheet - PH3430AL_1	Document ID	Release date	Data sheet status	Change notice	Supersedes
PH3430AL_4 20091204 Product data sheet - PH3430AL_3 PH3430AL_3 20091203 Product data sheet - PH3430AL_2 PH3430AL_2 20091126 Product data sheet - PH3430AL_1	PH3430AL_5	20100114	Product data sheet	-	PH3430AL_4
PH3430AL_3 20091203 Product data sheet - PH3430AL_2 PH3430AL_2 20091126 Product data sheet - PH3430AL_1	Modifications:	 Various cha 	anges to content.		
PH3430AL_2 20091126 Product data sheet - PH3430AL_1	PH3430AL_4	20091204	Product data sheet	-	PH3430AL_3
	PH3430AL_3	20091203	Product data sheet	-	PH3430AL_2
PH3430AL_1 20090121 Product data sheet	PH3430AL_2	20091126	Product data sheet	-	PH3430AL_1
-	PH3430AL_1	20090121	Product data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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